

Specification, Environment, and Test Plan Driven Test Bench Development

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1

Easily Updateable Testbenches

- A key to lowering life cycle support cost
- As a system evolves, model testing requirements frequently change
- Model tests are encapsulated in the testbenches

2

Premise

Testbenches should:

- Be automatically driven by specification requirements
- Accurately reflect the system environment
- Be configured by a test plan

3

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Approach

- Use existing tools as much as possible
- Tool types:
 - Code Generators: develop testbench code from high level, graphics based models (Ilogix-Express VHDL, SPW, Ptolemy, COSSAP)
 - Environmental Data Generators: SPW,xpatch, IRTOOL, and IRAMP data base.
- Required knowledge cuts across traditional engineering boundaries

4

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Two Applications

- SAR: model radar signals
 - transmission, return delay, down converting, deramping, and type conversion
 - one dimensional test case
- Infrared Search and Track : model pixel arrays
 - target image, background clutter, merging, noise injection
 - two dimensional test case

5

Specification Repository

- High level system block diagram
- Blocks correspond to real system components, underlying VHDL hidden.
- Implemented with a commercial schematic capture tool (Synopsys SGE)
- Specification parameters are symbol attributes
- Parser extracts specification values & feeds them forward to Test Bench Generator

6

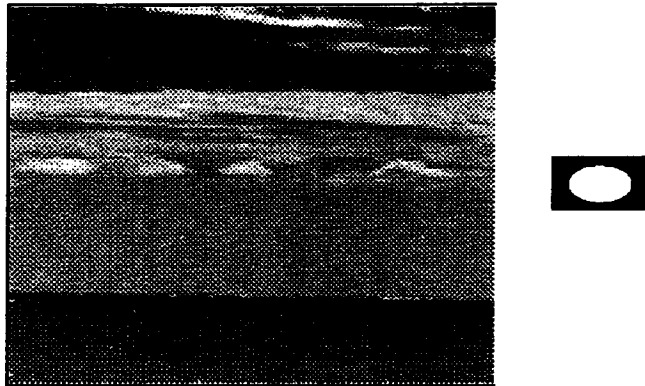
Accurate Environmental Modeling

- Principles:
 - Use tools specific to the physical environment
 - Convert data formats to those required by the test bench
 - Employ strategies for reading and manipulating large arrays of data

IRST Environmental Modeling

- IRTOOL (Arete')
 - Infrared returns from selected object shapes
 - Format conversion from HDF to ASCII
- IRAMP
 - data base of clutter files maintained by NRL
 - two dimensional images of sea & clouds
- Sensor noise and dropout
- Data loading times: 10 sec

Example: Background image from IRAMMP database and
example target signature created using IRTool



11

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SAR Environmental Modeling

- SPW real number model of transmission, return delay, down converting, deramping, and format conversion
- Superposition of simple object returns
- Also data files from MIT, Lockheed, and xpatch
- Memory storage and read time for large files

12

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Test Plan Interface

- Test plan: a document which organizes system requirements in terms of how the requirements will be tested.
- Requirements divided into groups, a set of tests is allocated to each group.

13

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Library Based Testbench Construction

- For each application (SAR or IRST), the testbench is an unbound, structural architecture.
- Each test is mapped to a VHDL configuration body of that architecture.
- Configuration body specifies which library to component to use and assigns values to generics.
- Test groups correspond to partially specified configurations.

14

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Testbench Component Libraries

- SAR:
 - High level: Genchirp, delay,downconverter, deramper,decimate,merge,noise
 - Low level: chirp,complex tone,complex multiply, delay, complex conjugate, decimate, type conversion
- IRST: target, clutter, sensor, clock

15

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Demonstration SAR Test Plan

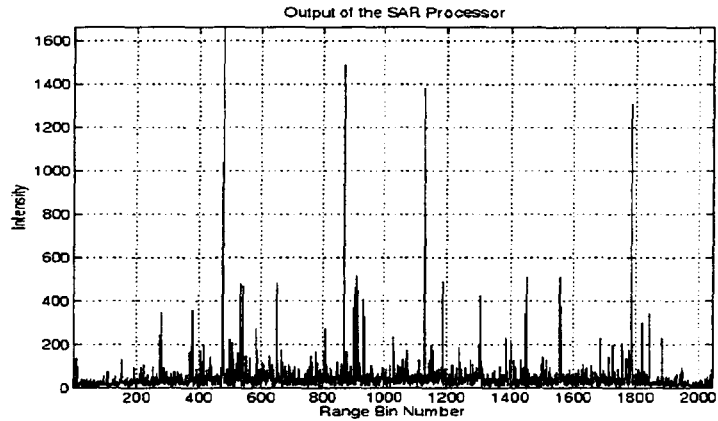
- Evaluate the range of a point target
- Evaluate the range of multiple point targets
- Evaluate resolution of SAR MUT.
- Evaluate SAR algorithm noise sensitivity

16

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Testplan 2
4 targets at range bins of
476,869,1131,1787. (Ranges of 7140,7230,
7290,7410 m.)

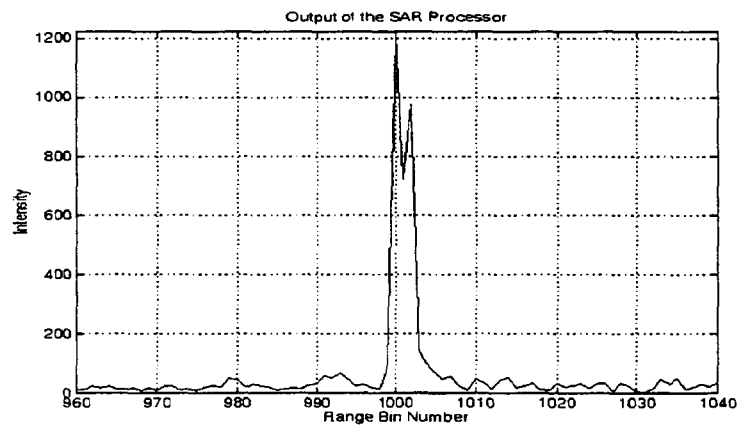


17

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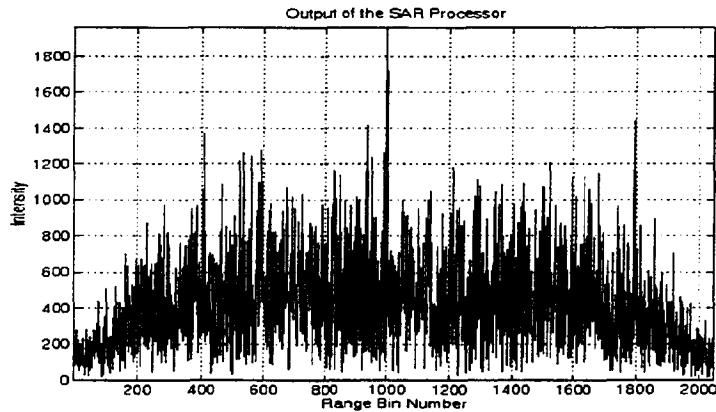
Testplan 3
Reference target at 7260 m (range bin 1000)
2nd target at 7260.19 m (range bin 10002)
(can be resolved)



18

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A test case of Testplan 4 (with Gaussian noise of
sigma=9.4) SNR= - 35dB
(when sigma \geq 9.5, the post filter reports ghost targets)

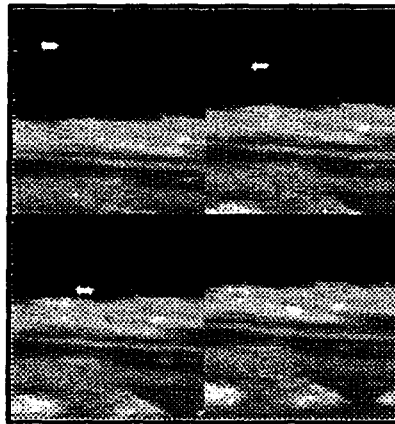


Demonstration IRST Test Plan

- Simple target detection
- Target detection with platform motion
- Target detection with sensor gain variations across the array
- Target detection with sensor noise
- Target detection with background clutter variation.

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An example of continuous frames generated by the testbench with artificial target (includes target motion, platform motion and sensor noise)



21

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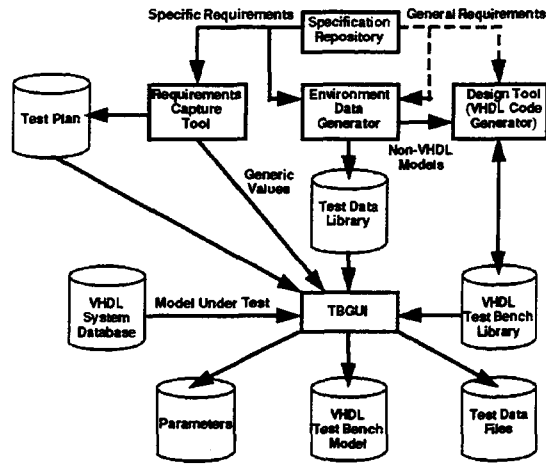
Systems Integration Work

- Existing design and application area tools can be used to develop pieces of a testbench.
- Two software systems integrate the pieces:
 - Test Bench Generation System
 - User Interface: TBGUI
 - VHDL Test Simulation Controller
 - User Interface: TBEUI

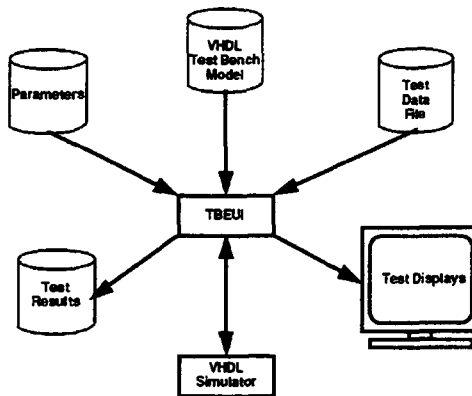
22

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Test Bench Generation System



The VHDL Test Simulation Controller



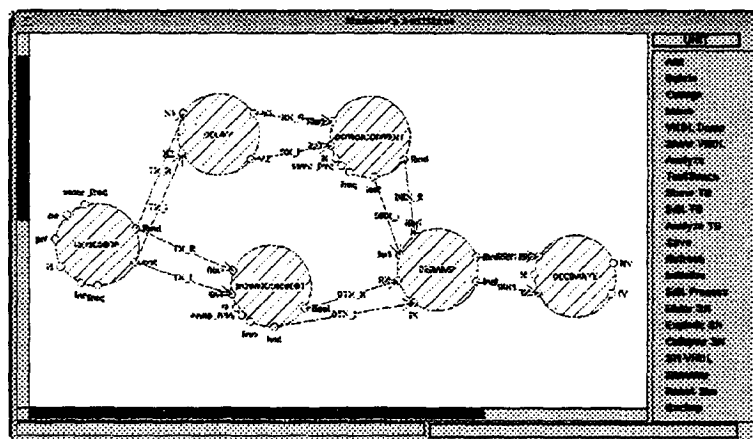
Modeling Support Tool

- Modeler's Assistant
- Models constructed from Process Model Graph and Process Primitive Library
- Provides for process level code reusability
- RASSP processes primitive libraries for IRST and SAR
- Tool available through WWW site:
http://vtdal7.dal.ee.vt.edu/MODAS/modas_home.html

25

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PMG of SAR Sensor (MODAS)



26

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Conclusions

- Effective testbench generation requires:
 - Automatic linkage to the system specification
 - Accurate environmental modeling
 - A test bench component library
 - A test plan interface to configure the test bench structural architecture
- Commercial tool suite used for generation of test bench pieces.
- Software systems developed for test bench generation and simulation control